











SN74AHCT367

SCLS418H -JUNE 1998-REVISED DECEMBER 2014

SN74AHCT367 Hex Buffer and Line Driver with 3-State Output

Features

- Inputs are TTL-Voltage Compatible
- **True Outputs**
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model
 - 200-V Machine Model
 - 2000-V Charged-Device Model

Applications

- Telecom Infrastructure
- **TVs**
- Set Top Boxes
- **Network Switches**
- Wireless Infrastructure
- Electronic Points of Sale

3 Description

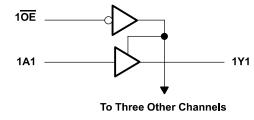
The SN74AHCT367 device is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
	PDIP (16)	19.30 mm x 6.35 mm
	SSOP (16)	6.50 mm x 5.30 mm
SN74AHCT367	TSSOP (16)	5.00 mm x 4.40 mm
	SOP (16)	10.20 mm x 5.30 mm
	SOIC (16)	9.00 mm x 3.90 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic



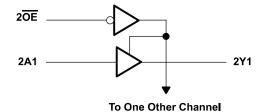




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5 Revision History

Changes from Revision G (July 2003) to Revision H

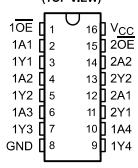
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Added Applications, Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Typical Characteristics, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section.
Deleted Ordering Information table.
MAX operating temperature to 125°C in Recommended Operating Conditions table.



6 Pin Configuration and Functions

SN74AHCT367 . . . D, DB, DGV, OR PW PACKAGE (TOP VIEW)



Pin Functions

PIN		TVDE	DESCRIPTION			
NO.	NAME	TYPE	DESCRIPTION			
1	1 OE	ı	Output Enable 1			
2	1A1	I	1A1 Input			
3	1Y1	0	1Y1 Output			
4	1A2	I	1A2 Input			
5	1Y2	0	1Y2 Output			
6	1A3	I	1A3 Input			
7	1Y3	0	1Y3 Output			
8	GND	_	Ground Pin			
9	1Y4	0	1Y4 Output			
10	1A4	I	1A4 Input			
11	2Y1	0	2Y1 Output			
12	2A1	I	2A1 Input			
13	2Y2	0	2Y2 Output			
14	2A2	I	2A2 Input			
15	2 OE	ı	Output Enable 2			
16	V _{CC}	_	Power Pin			

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7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_{O} = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GN		±75	mA	
T _{stg}	Storage temperature range	– 65	150	°C	

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins (1)	2000	
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	2000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

		SN74AHC1	Г367	LIMIT
		MIN	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.5	V
V _{IH}	High-level input voltage	2		V
V _{IL}	Low-level Input voltage		0.8	V
VI	Input voltage	0	5.5	V
Vo	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current		-8	mA
I _{OL}	Low-level output current		8	mA
Δt/Δν	Input transition rise or fall rate		20	ns/V
T _A	Operating free-air temperature	-40	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs (SCBA004).

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⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



7.4 Thermal Information

			SN74AHCT367				
	THERMAL METRIC ⁽¹⁾	D	DB	DGV	PW	UNIT	
			16 [PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	85.1	103.9	124.5	111.5		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	46.5	54.3	49.8	46.5		
$R_{\theta JB}$	Junction-to-board thermal resistance	42.6	54.6	56.2	56.6	°C/W	
ΨЈТ	Junction-to-top characterization parameter	13.2	14.3	5.8	5.8		
Ψ_{JB}	Junction-to-board characterization parameter	42.4	54.0	55.7	56.0		

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

7.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

DADAMETED	ARAMETER TEST CONDITIONS V		T _A	= 25°C		–40°C to 8	85°C	-40°C to 12	25°C	UNIT
PARAMETER			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
V	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
V _{OH}	I _{OH} = –8 mA	4.5 V	3.94			3.8		3.8		V
V _{OL}	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	I _{OH} = 8 mA	4.5 V			0.36		0.44		0.44	v
l ₁	V _I = 5.5 V or GND	0 V to 5.5 V			±0.1 ⁽¹⁾		±1 ⁽¹⁾		±1	μΑ
l _{oz}	$V_O = V_{CC}$ or GND $V_I (\overline{OE}) = V_{IL}$ or V_{IH}	5.5 V			±0.25		±2.5		±2.5	μΑ
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40		40	μΑ
ΔI _{CC} ⁽²⁾	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5		1.5	mA
C _i	V _I = V _{CC} or GND	5 V		2.5	10		10		10	pF
Co	V _O = V _{CC} or GND	5 V		5						pF

7.6 Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	LOAD	T _A = 2	5°C	–40°C to	85°C	–40°C to	125°C	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	TYP	MAX	MIN	MAX	MIN	MAX	UNII		
t _{PLH}	1 A	Y	C ₁ = 15 pF	2.5 ⁽¹⁾	4.8 ⁽¹⁾	1	6.5	1	8.5	ns		
t _{PHL}	^	1	OL - 15 pr	2.5 ⁽¹⁾	4.8 ⁽¹⁾	1	6.5	1	8.5	115		
t _{PZH}	ŌĒ	Υ	C ₁ = 15 pF	3.5 ⁽¹⁾	8 ⁽¹⁾	1	9.5	1	9	ns		
t _{PZL}	J	Y	C _L = 15 pr	2.8 ⁽¹⁾	7 ⁽¹⁾	1	8.5 ⁽¹⁾	1	8	115		
t _{PHZ}	ŌĒ	Y	C _L = 15 pF	3.1 ⁽¹⁾	8 ⁽¹⁾	1	9.5	1	9	no		
t _{PLZ}	OE		'	'	T T	C _L = 15 pr	2.8 ⁽¹⁾	7 ⁽¹⁾	1	8.5	1	8
t _{PLH}	A	Υ	C = 50 nE	3.5	5.8	1	7.5	1	9.5	no		
t _{PHL}	^	Y	Y $C_L = 50 \text{ pF}$	Y	3.3	5.8	1	7.5	1	9.5	ns	
t _{PZH}	ŌĒ	Υ	C ₁ = 50 pF	4.5	9	1	10.5	1	10	no		
t _{PZL}	J	Y	CL = 50 pr	3.7	8	1	9.5	1	9	ns		
t _{PHZ}	ŌĒ	Υ	C ₁ = 50 pF	4.1	9	1	10.5	1	10	ne		
t _{PLZ}	OL	1	CL = 50 pr	3.6	8	1	9.5	1	9	ns		

⁽¹⁾ On products compliant to MIL-PRF-38535, this parameter is not production tested.

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⁽¹⁾ On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0 V. (2) This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V_{CC} .



7.7 Noise Characteristics

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}C^{(1)}$

	PARAMETER		SN74AHCT367		
			TYP MA	UNIT	
$V_{OL(P)}$	Quiet output, maximum dynamic V _{OL}		0.4	V	
$V_{OL(V)}$	Quiet output, minimum dynamic V _{OL}		-0.4	V	
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.7	V	
$V_{IH(D)}$	High-level dynamic input voltage	2		V	
$V_{IL(D)}$	Low-level dynamic input voltage		C	.8 V	

⁽¹⁾ Characteristics are for surface-mount packages only.

7.8 Operating Characteristics

 V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT	
C _{pd} Power dissipation capacitance	No load, f = 1 MHz	22	pF	

7.9 Typical Characteristics

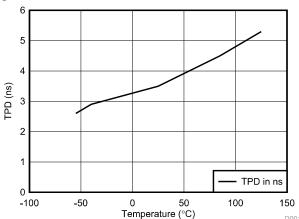
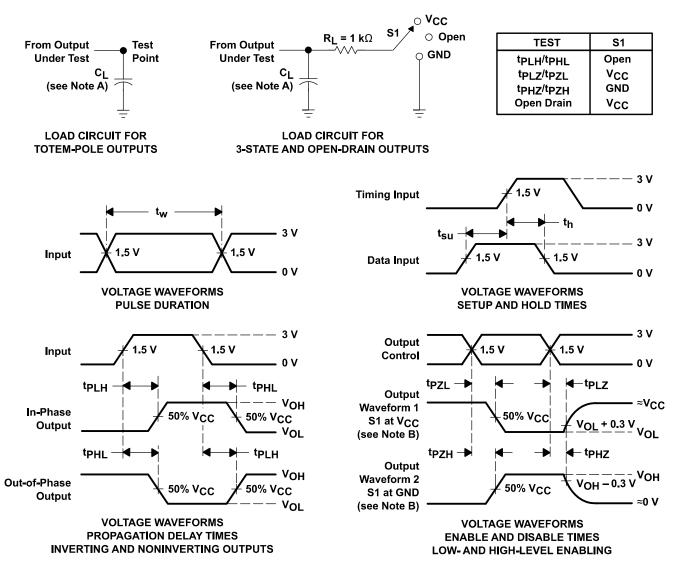


Figure 1. TPD vs Temperature, 50 pF Load



8 Parameter Measurement Information



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , $t_f \leq$ 3 ns. $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms



9 Detailed Description

9.1 Overview

The SN74AHCT367 device is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. This device is organized as a dual 4-line and 2-line buffer/driver with active-low output-enable (1OE and 2OE) inputs. When OE is low, the device passes noninverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pull-up resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

9.2 Functional Block Diagram



Figure 3. Logic Diagram (Positive Logic)

9.3 Feature Description

- V_{CC} is optimized at 5 V
- Allows up voltage translation from 3.3 V to 5 V
 - Inputs Accept V_{IH} levels of 2 V
- · Slow edge rates minimize output ringing
- Inputs are TTL-Voltage compatible

9.4 Device Functional Modes

Table 1. Function Table (Each Buffer/Driver)

INP	UTS	OUTPUT
ŌĒ	Α	Y
Н	X	Z
L	Н	Н
L	L	L

Product Folder Links: SN74AHCT367



10 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

10.1 Application Information

SN74AHCT367 is a low-drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low drive and slow edge rates will minimize overshoot and undershoot on the outputs. The input switching levels have been lowered to accommodate TTL inputs of 0.8-V V_{IL} and 2-V V_{IH} . This feature makes it Ideal for translating up from 3.3 V to 5 V. Figure 5 shows this type of translation.

10.2 Typical Application

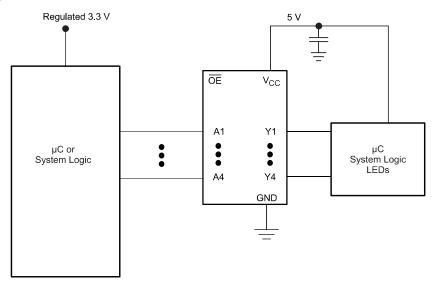


Figure 4. Typical Application Schematic

10.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads, so routing and load conditions should be considered to prevent ringing.

10.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions
 - For rise time and fall time specifications, see Δt/ΔV in the Recommended Operating Conditions table.
 - For specified High and low levels, see V_{IH} and V_{IL} in the Recommended Operating Conditions table.

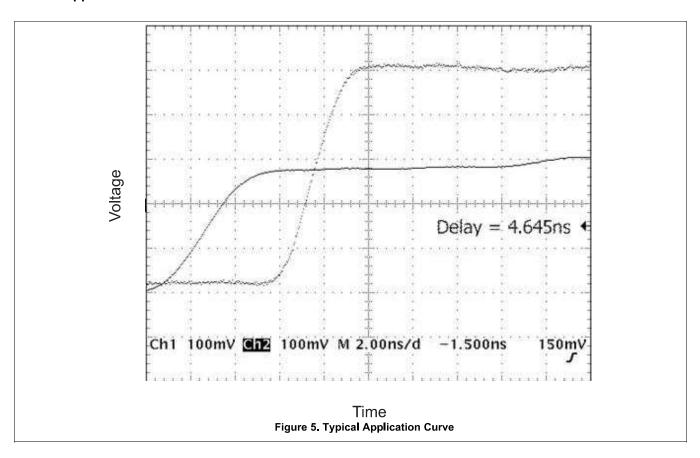
Product Folder Links: SN74AHCT367

- Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V_{CC}.
- 2. Recommend Output Conditions
 - Load currents should not exceed 25 mA per output and 75 mA total for the part.
 - Outputs should not be pulled above V_{CC}.



Typical Application (continued)

10.2.3 Application Curves



11 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the *Recommended Operating Conditions* table.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, 0.1 μ F is recommended. If there are multiple V_{CC} pins, 0.01 μ F or 0.022 μ F is recommended for each power pin. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. A 0.1 μ F and 1 μ F are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.



12 Layout

12.1 Layout Guidelines

When using multiple bit logic devices, inputs should not float. In many cases, functions or parts of functions of digital logic devices are unused. Some examples are when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Figure 6 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} , whichever makes more sense or is more convenient. It is acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the outputs section of the part when asserted. This will not disable the input section of the I/Os so they also cannot float when disabled.

12.2 Layout Example

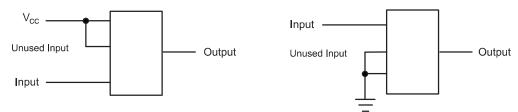


Figure 6. Layout Diagram

13 Device and Documentation Support

13.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 2. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
SN74AHCT367	Click here	Click here	Click here	Click here	Click here

13.2 Trademarks

All trademarks are the property of their respective owners.

13.3 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

13.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: SN74AHCT367